

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/615,876 HIKITA ET AL.	
		Examiner	Art Unit	Page 1 of 1 David A. Zameke 2829

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,150,724	11-2000	Wenzel et al.	257/777
	B	US-5,155,065	10-1992	Schweiss, Helmut	438/599
	C	US-5,319,224	06-1994	Sakashita et al.	257/203
	D	US-5,585,676	12-1996	Uda et al.	257/786
	E	US-5,965,948	10-1999	Okamoto, Kohei	257/786
	F	US-5,909,055	06-1999	Yamashita et al.	257/693
	G	US-5,455,460	10-1995	Hongo et al.	257/734
	H	US-5,153,507	10-1992	Fong et al.	324/764
	I	US-6,590,297	07-2003	Sasaki, Masao	257/786
	J	US-4,990,996	02-1991	Kumar et al.	257/786
	K	US-4,195,195	03-1980	de Miranda et al.	174/254
	L	US-6,111,756	08-2000	Moresco, Larry L.	361/735
	M	US-2004/0089717	05-2004	Harari et al.	235/441

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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